Search Notes

**	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/812,151	LABRASH, RICHARD
	Examiner	Art Unit
	Alvin C. Chin-Shue	3634

	SEAR	CHED	
Class	Subclass	Date	Examiner
182	97 95 206	6.2.06	M
	95		
	206		
280	166		
280	166		
	,		
		,	
	•••		

INT	ERFERENCE SEARCHED		
Class	Subclass	Date	Examiner

SEARCH (INCLUDING SEA	NOTES RCH STRATEGY	<b>(</b> )
	DATE	EXMR
-		
		: